


Search Notes 	Application/Control No. 10517214	Applicant(s)/Patent Under Reexamination MAEKAWA ET AL.
	Examiner Jaisle, Cecilia M	Art Unit 1624

SEARCHED			
Class	Subclass	Date	Examiner
514	403, 404	8/12/2009	Cecilia Jaisle
548	373.1, 375.1	8/12/2009	Cecilia Jaisle
546	275.4, 276.4	8/12/2009	C. Jaisle
544	238	8/12/2009	CJ

SEARCH NOTES		
Search Notes	Date	Examiner
STN and Inventor Names searched by STIC	10/10/2007	Cecilia Jaisle

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
514	403, 404	8/12/2009	C. Jaisle
548	373.1, 375.1	8/12/2009	C. Jaisle
546	275.4, 276.4	8/12/2009	CJ
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